

### QUALIFICATION REPORT SUMMARY

PACKAGE	TEST	CONDITIONS	SAMPLE SIZE	RESULTS
14-SOIC_N	Temperature Cycle (TC) <sup>1</sup>	JEDEC <i>JESD22-A104</i>	1 x 77	Pass
14-SOIC_N	Autoclave (AC) <sup>1</sup>	JEDEC <i>JESD22-A102</i>	1 x 77	Pass
14-SOIC_N	Solder Heat Resistance (SHR) <sup>1</sup>	<i>ADI-0049</i>	1 x 30	Pass
14-TSSOP_4.4	Highly Accelerated Stress Test (HAST) <sup>1,2</sup>	JEDEC <i>JESD22-A110</i>	3 x 77	Pass
14-TSSOP_4.4	Temperature Cycle (TC) <sup>1,2</sup>	JEDEC <i>JESD22-A104</i>	3 x 77	Pass
14-TSSOP_4.4	Autoclave (AC) <sup>1</sup>	JEDEC <i>JESD22-A102</i>	3 x 77	Pass
14-TSSOP_4.4	High Temperature Storage Life (HTSL)	JEDEC <i>JESD22-A103</i>	1 x 77	Pass
14-TSSOP_4.4	Solder Heat Resistance (SHR) <sup>1</sup>	<i>ADI-0049</i>	1 x 30	Pass
14-SOIC_N	Latch-Up	JEDEC <i>JESD78</i>	1 x 9	Pass
14-SOIC_N	Electrostatic Discharge <i>Human Body Model</i>	ANSI/ANSI/ESDA/JEDEC <i>JS-001-2010</i>	1 x 24	Pass 4kV
14-SOIC_N	Electrostatic Discharge <i>Field-Induced Charged Device Model</i>	JEDEC <i>JESD22-C101</i>	1 x 15	Pass 1.5kV
14-TSSOP_4.4	Electrostatic Discharge <i>Field-Induced Charged Device Model</i>	JEDEC <i>JESD22-C101</i>	1 x 15	Pass 1.5kV

<sup>1</sup> Preconditioned per JEDEC/IPC J-STD-020

<sup>2</sup> Test is not a Gating item for Reliability Qualification